AI BASED DEFECT DETECTION FOR NON-DESTRUCTIVE INSPECTION

ABSTRACT

The present disclosure provides methods and techniques for anomaly detecting using feature matching models. A plurality of normal images are received. A plurality of patch features are generated by processing each of the plurality of normal images. A coreset comprising one or more coreset samples is generated, where the one or more coreset samples are selected from the plurality of patch features. A test image is received. One or more test patch features are generated by processing the test image. An anomaly score is generated by comparing the one or more test patch features with the one or more coreset samples.

Fig. 8